WaferPro Express
2016.04

WaferPro Express 2016_04 Release Notes

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WaferPro Express 2016.04 Hotfix 2 Release Notes

Release: Nov 25, 2016

Version

722.hf2

Enhancements

- A-LFNA Noise Measurement speed enhancement: ~1.6x for 1/f noise, ~10x-30x for RTN measurements.
- Large number of data samples supported, that is up to 16 million (=2^24) points, for RTN measurements.
- Added FFT window function (Hanning) for A-LFNA.

Issues Addressed

- Resolved memory leak issue in A-LFNA.
- Modified Rout (output resistance) calculation to avoid error and to get smoother data trace in A-LFNA.
- Repaired A-LFNA Gain measurement not having worked for Circuit.
- Fixed a measurement error for Circuit when changing AMP in the Noise Setup window.
- Fixed an RTN measurement error when using a small value for Time_Step (< 2.5nsec).
- Repaired B2200A_01 Matrix driver issue of the offset pins incorrectly calculated for values under 10.
- Repaired to avoid saving dynamic routine changes during measurements to file.
- Resolved the Load Wafer button issue in the Hardware Connections window by adding wafer selection pull-down list.

Notes

- For this new A-LFNA version, the digitizer driver needs to be updated. See Installing Digitizer Driver. Also, you can access the digitizer driver information in the PDF format at: <Install_Dir>/alfna/drivers /how_to_install_digitizer_driver.pdf.

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